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PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10029390	FILING DATE 12/28/2001	CLASS 324.133	SUBCLASS 18	GAU 2858	EXAMINER PERT
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\*\*CONTINUING DATA VERIFIED:

\*\* FOREIGN APPLICATIONS VERIFIED:  
REPUBLIC OF KOREA 2001-73419 11/23/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO	
35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no		054216-5024	
Verified and Acknowledged Examiners's initials			
TITLE : Test pattern for measuring contact resistance and method of manufacturing the same			
U.S. DEPT. OF COMM./PAT. & TM-PTO-436L (Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg.
			Print Fig.
Assistant Examiner		Application Examiner	
Primary Examiner			
PREPARED FOR ISSUE			
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